



February 5-8, 2018 Big Island, Hawaii

The Best of Today, A Preview of Tomorrow

Monday, February 5th

**Designates Distinguished Speaker*

TIME	LOCATION	
2:00p-5:30p	Foyer	REGISTRATION
		Plenary Keynote Session Chair: Chuck Bauer, Ph.D., TechLead Corporation
3:00p-3:35p	Lehua/Hau	From Weapons to Wirebonds: How Global Security Drives Innovation, Supply, and Demand Martin Goetz, Northrop Grumman Corporation
3:35p-4:10p	Lehua/Hau	The Latest Material Technologies For System in Package *Osamu Suzuki, Namics Corporation
4:10p-4:20p	Great Room	Welcome Message from Phil Isaacs, IBM Corporation
4:20p-4:55p	Lehua/Hau	Management of Complexity in Research and Development Work *Verena Hein, 4academy
4:55p-5:30p	Lehua/Hau	Selected Highlights From the 2017 iNEMI Roadmap and Key Projects to Address Identified Gaps Bill Bader, iNEMI
5:30p-6:30p	Breezeway	WELCOME RECEPTION

Tuesday, February 6th

TIME	LOCATION	Session 1 - Automotive Systems & Hardware	LOCATION	Session 2 - Materials & Reliability
8:30a-9:00a	Lehua/Hau	Reliability Engineering Techniques for Consumer Products *John Cooper, P.E. CRE, MSEE, Ops A La Carte, LLC	Milo	Intermetallic Compound Formation and Mechanical Property of Sn-Cu-xCr/Cu Lead-Free Solder Joint Bang Junghwan, Dong-Yurl Yu, Yong-Ho Ko, Min-Su Kim, Hiroshi Nishikawa, Chang-Woo Lee Korea Institute of Industrial Technology
9:00a-9:30a	Lehua/Hau	"New Automotive" - Considerations for Reliability, Robustness and Resilience for CMOS Interconnects *Kirsten Weide-Zaage, Ph.D., University of Hannover; *Verena Hein, X-FAB AG; H�el�ene Fr�emont, Ph.D., Universit�e de Bordeaux	Milo	A Flowers of Sulfur Corrosion Chamber For Testing Electronic Hardware *Prabjit Singh, Ph.D., Larry Palmer, IBM Corporation; Haley Fu, iNEMI; Dem Lee, Jeffrey Lee, IST-Integrated Service Technology, Inc.; Karlos Guo, Jane Li Lenovo, Limited Corporation; Simon Lee, Geoffrey Tong, The Dow Chemical Company; Chen Xu, Nokia
9:30a-10:00a	Lehua/Hau	Enhanced Driver Safety With Advanced Vision Systems *Dwight Howard, Delphi Automotive, LLC	Milo	Long-Term Isothermally Aged Concerns for SAC Lead-Free Solder in Harsh Environment Applications *John Evans, Ph.D., Auburn University
10:00a-10:15a	Courtyard	REFRESHMENT BREAK		
10:15a-10:45a	Lehua/Hau	Validated Physics of Failure Approaches for Automotive Reliability Assurance *Dock Brown, CRE, DfR Solutions	Milo	Using Cpk and Cpk Confidence Intervals to Evaluate Stencil Printing *Ron Lasky, Ph.D., P.E., Chris Nash, Indium Corporation
11:00a-11:45a	Lehua/Hau	Symposium Keynote I : Honda's New Mobility System Development Challenge; Key Functions and Devices for Intelligent Mobility System Yoshiaki Sakagami, Honda		
11:45a-12:45p	Breezeway	LUNCH BREAK		
		Session 3- Inspection & Test Techniques		Session 4- Cleaning Technologies
12:45p-1:15p	Lehua/Hau	IPC-1972 Standard for Traceability of Critical Items Based on Risk *Cameron Shearon, Shearon-Consulting	Milo	Cleanliness Testing for Process Acceptability *Mark McMeen, Jonnie Johnson, Collin Langley, STI Electronics; *Mike Bixenman, DBA, David Lober, Kyzen Corporation

1:15p-1:45p	Lehua/Hau	Comprehensive Study of Various Short Failures on Printed Circuit Board Xiao He, Baojun Qiu, Daojun Luo, CEPREI	Milo	Evaluation of No-Clean Flux Residues Remaining after Secondary Operations *Phil Isaacs, Jennifer Porto, IBM Corporation; *Terry Munson, Foresite, Inc.
1:45p-2:15p	Lehua/Hau	Advances in Computer Tomography (3D) for Demanding Electronics Applications *Keith Bryant, Yxlon International	Milo	Ion Chromatography Component Specific Cleanliness Testing for Process Acceptability *Mike Bixenman, DBA, Dave Lober, Kyzen Corporation; *Mark McMeen, Collin Langley, STI Corporation
2:15p-2:45p	Lehua/Hau	Recent Applications of Fourier Domain Imaging of Microelectronic Devices Janet Semmens, Sonoscan, Inc.	Milo	Problems with R.O.S.E. Testing using Today's Fluxes Todd Rountree, *Steve Stach Austin American Technology Corporation
2:45p-3:00p	Courtyard	REFRESHMENT BREAK		
		Session 5- Advanced Materials Chair: *Ron Lasky, Ph.D., P.E., Indium Corporation		
3:00p-3:30p	Lehua/Hau	Oxygen Vacancy Migration in MLCCs *Dock Brown, CRE, DfR Solutions		
3:30p-4:00p	Lehua/Hau	Update on Cu-Ni/Sn Alloy Composite Solder Paste for Harsh Environments Stephanie Choquette, Ph.D., Iowa State University; Iver Anderson, Ames Laboratory (USDOE)		
4:00p-4:30p	Lehua/Hau	Resistivity Stain Analysis of Graphene Coated Fabric for Wearable Electronics *Martine Simard-Normandine, Ph.D., S. Ferguson, MuAnalysis Inc.; K. Manga, Q.-B. Ho Grafoid		
4:30p-5:00p	Lehua/Hau	Low Melt Solder Applications and Reliability Panel Panelists TBD		

Wednesday, February 7th

TIME	LOCATION	Session 6- Interposer & Packaging Technology	LOCATION	Session 7- Advanced Processes & Packaging
8:30a-9:00a	Lehua/Hau	Disparities in Packaging Technologies and the Alternative Methods for Assembly: The AREA Consortium Roadmap *David Vicari, Universal Instruments	Milo	Development of High Reliability Photosensitive Polyimide for RDL of FO-WLP Masao Tomikawa, Ph.D., Toray Industries
9:00a-9:30a	Lehua/Hau	Highly Accurate Wiring Fabrication Technologies By Plasma Dry Processes for 3D-IC and Fan-Out Packaging Yasuhiro Morikawa, ULVAC, Inc.	Milo	Challenges in Material Selection for SiP Applications Sze Pei Lim, Andy Mackie, Ph.D., Kenneth Thum, Indium Corporation
9:30a-10:00a	Lehua/Hau	Place-N-Bond Flex Applications *Randy Temple, Alltemated Inc.	Milo	Process, Geometry and Stack Related Reliability of Thick AlCu-Metal-Tracks *Kirsten Weide-Zaage, Ph.D., University of Hannover; *Verena Hein, X-FAB AG
10:00a-10:15a	Courtyard	REFRESHMENT BREAK		
10:15a-10:45a	Lehua/Hau	Smarter-SI - Smart Access to Manufacturing for Systems Integration *Dag Andersson, Ph.D., Swerea	Milo	Robotic Soldering of Lead Free Alloys Thomas Truman, Kar Lin Chia, Ban Leong Choo, Sooi Jin Lee, Cynthia Tan Sok Luang, Ming Siew Tan, Kelvin Ho Ngee Boon, Venture Corporation Limited
10:45a-11:15a	Lehua/Hau	Title TBD Bill Chen, ASE (US) Inc.		
11:30a-12:15p	Lehua/Hau	Symposium Keynote II: Integrated Intelligent Transportation And Key Enablers *Dwight Howard, Delphi Automotive, LLC		
12:15p-1:15p	Breezeway	LUNCH BREAK		
		Session 8- Nanotechnology Applications		Session 9- Advanced Packaging & Processes
1:15p-1:45p	Lehua/Hau	Making SiPs More Reliable Using Plasma-Based Nanocoating for Solder Joint Top Coat Simone McElrea, M.Eng., Semblant	Milo	Influence of Electroless Pd Plating Thickness on Solder Ball Joint Reliability *Yoshinori Ejiri, Takehisa Sakurai, Yoshinori Arayama, Yoshiaki Tsubomatsu, Kiyoshi Hasegawa, Hitachi Chemical Co., Ltd.
1:45p-2:15p	Lehua/Hau	The Development of Test Methodologies for Determining the Formulations and Mechanical Properties of Lead Free Nano Solder Sammy Shina, Ph.D., P.E., Irtiza Akhtar, UMASS Lowell	Milo	Fabrication of 2D and 3D Inductances for DC-DC Converter Integrated on Glass Interposer Vincent Lafage, Ph.D., Dominique Drouin, Yann Beilliard, Laboratoire Nanotechnologies Nanosystemes (LN2) Université de Sherbrooke

2:15p-2:45p	Lehua/Hau	Controlling Electric Power In Local Joule Heating to Reduce Contact Resistance of Carbon Nanotubes Libao An, Ph.D., North China University of Science and Technology	Milo	Design and Reliability Assessment of Stacked Fan-Out Packaging Pao Hsiung Wang, Ph.D., An Huang, Kuo-Ning Chiang, Department of Power Mechanical Engineering, National Tsing Hua University
2:45p-3:15p	Lehua/Hau	Applications of Nanotechnologies to Biomedicine Ivo Rendina, National Research Council, IMM	Milo	Uniformity Consideration in Capacitively Coupled Plasma Jack Zhao, Ph.D., Nordson March
3:15p-3:30p	Courtyard	REFRESHMENT BREAK		
		Session 10- Advanced Process		
3:30p-4:00p	Lehua/Hau	Deposit Properties of New Electroless Au/Pd/Au Process for Fine Line Application Tatsushi Someya, Katsuhisa Tanabe, C. Uyemura & Co., Ltd.		
4:00p-4:30p	Lehua/Hau	Etching Behaviors of Galvanic Coupled Metals in PCB Applications Jae-Ho Lee, Ph.D., Hongik University		
4:30p-5:00p	Lehua/Hau	Pb-Free Solders and Other Joining Materials for Potential Replacement of High-Pb Hierarchical Solders Iver Anderson, Ames Laboratory (USDOE), Stephanie Choquette, Iowa State University; Kathlene L. Reeves and Carol Handwerker, Purdue University		
5:30p-6:00p	Breezeway	MAI TAI BAR AND NETWORKING		

Thursday, February 8th

TIME	LOCATION	Session 11- Heterogeneous Integration		
8:30a-9:00a	Lehua/Hau	Heterogeneous Integration Technologies at the Device and System Levels *Rao Tummala, Ph.D., Georgia Institute of Technology		
9:00a-9:30a	Lehua/Hau	Enabline Information Age through Advanced Packaging Technologies and Electronic Materials Rozalia Beica, Dow Chemical		
9:30a-10:00a	Lehua/Hau	Title TBD M. Jürgen Wolf, P.E., Fraunhofer Institute of Reliability and Microintegration IZM		
10:00a-10:15a	Courtyard	REFRESHMENT BREAK		
10:15a-10:45a	Lehua/Hau	A Study on the Novel Anchoring Polymer Layer (APL) *Kyung Paik, Ph.D., KAIST		
10:45a-11:15a	Lehua/Hau	iNEMI Project on Process Development of BiSn-Based Low Temperature Solder Pastes Part II *Raiyo Aspandiar, Ph.D., Shunfeng Cheng, Bill Hardin, Scott Mokler, Ph.D., P.E., Jagadeesh Radhakrishnan, Kok Kwan Tang, Intel; Haley Fu, iNEMI; Jimmy Chen, Cooper Bussmann; *Richard Coyle, Ph.D., Nokia; *Morgana Ribas, Alpha Assembly Solutions; Brook Sandy-Smith, Anny Zhang, Indium Corporation; Mark Krmopotich, Microsoft Corporation; Greg Wu, Rantec Power Systems; Wilson Zhen, IBM Procurement China Limited; Qin Chen, Eunow; Sophia Feng, Celestica		
11:30a-12:15p	Lehua/Hau	Symposium Keynote III: Cost Effective Solutions for SiP and Miniaturized Modules Dongkai Shangguan, Ph.D., Flex		
12:15p-1:00p	Breezeway	Conference Concludes		
6:00p-9:00p	Pool Side	Private Luau		